FAST CMOS OCTAL D REGISTERS (3-STATE)

IDT54/74FCT374/A/C

FEATURES:

- **IDT54FCT374 equal to FAST™ speed and drive**
- **IDT54/74FCT374A up to 30% faster than FAST**
- **IDT74FCT374C up to 50% faster than FAST**
- **I_{OL} = 48mA (commercial) and 32mA (military)**
- **CMOS power levels (1mW typ. static)**
- **Edge-triggered master/slave, D-type flip-flops**
- **Buffered common clock and buffered common 3-state control**
- **MIlitary product compliant to MIL-STD-883, Class B**
- **Meets or exceeds JEDEC Standard 18 specifications**
- **Available in the following packages:**
  - *Commercial: SOIC*
  - *Military: CERDIP, LCC*

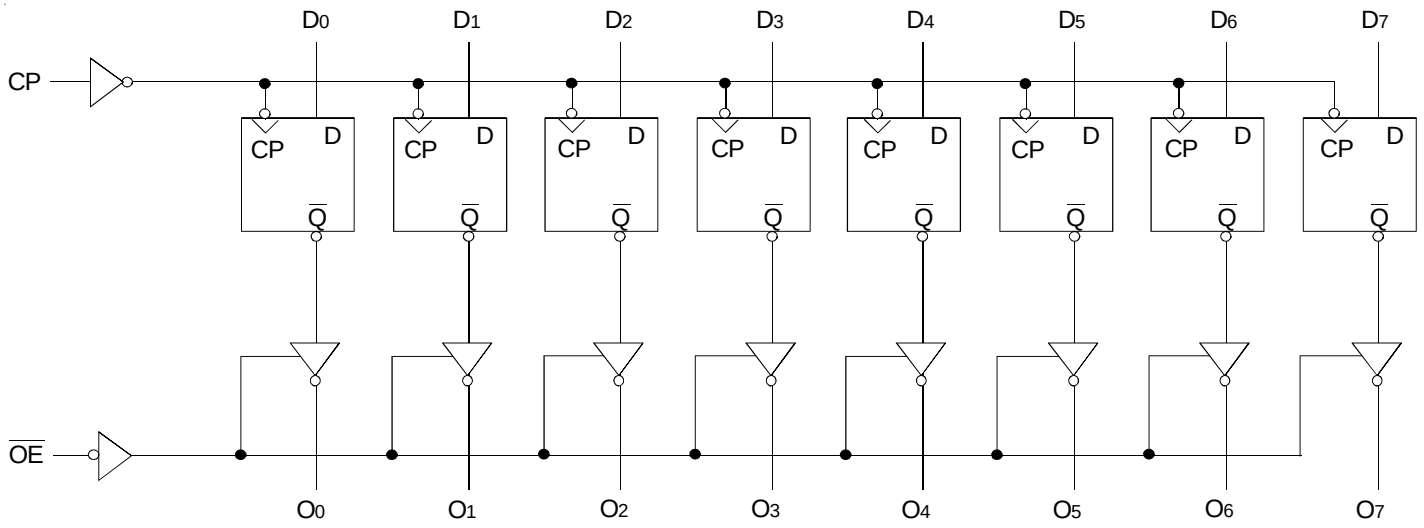
DESCRIPTION:

The FCT374 is an 8-bit register built using an advanced dual metal CMOS technology. These registers consist of eight D-type flip-flops with a buffered common clock and buffered 3-state output control. When the output enable ($\overline{OE}$) is low, the eight outputs are enabled. When the $\overline{OE}$ input is high, the outputs are in the high-impedance state.

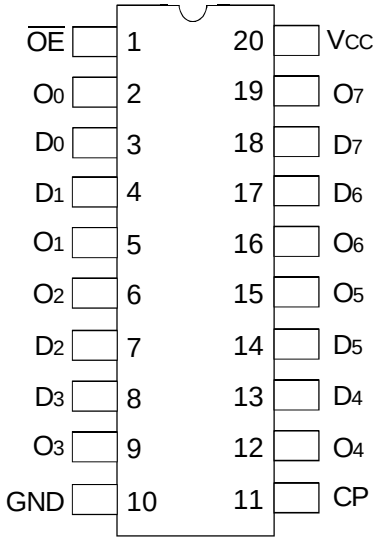
Input data meeting the set-up and hold time requirements of the D inputs is transferred to the O outputs on the low-to-high transition of the clock input.

The FCT374 has non-inverting outputs with respect to the data at the D inputs.

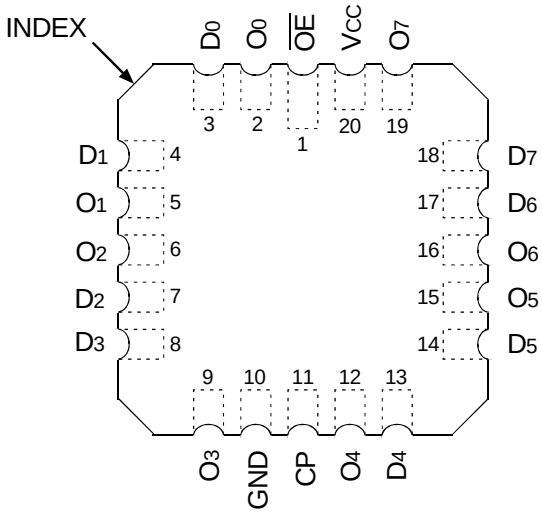
FUNCTIONAL BLOCK DIAGRAM



PIN CONFIGURATION



CERDIP/ SOIC
TOP VIEW



LCC
TOP VIEW

ABSOLUTE MAXIMUM RATINGS(1)

Symbol	Rating	Commercial	Military	Unit
V_{TERM}(2)	Terminal Voltage with Respect to GND	–0.5 to +7	–0.5 to +7	V
V_{TERM}(3)	Terminal Voltage with Respect to GND	–0.5 to V_{CC}	–0.5 to V_{CC}	V
T_A	Operating Temperature	0 to +70	–55 to +125	°C
T_{BIAS}	Temperature under BIAS	–55 to +125	–65 to +135	°C
T_{STG}	Storage Temperature	–55 to +125	–65 to +150	°C
P_T	Power Dissipation	0.5	0.5	W
I_{OUT}	DC Output Current	120	120	mA

NOTES:
1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability. No terminal voltage may exceed Vcc by +0.5V unless otherwise noted.
2. Input and Vcc terminals only.
3. Output and I/O terminals only.

CAPACITANCE (T_A = +25°C, F = 1.0MHz)

Symbol	Parameter(1)	Conditions	Typ.	Max.	Unit
C_{IN}	Input Capacitance	V_{IN} = 0V	6	10	pF
C_{OUT}	Output Capacitance	V_{OUT} = 0V	8	12	pF

NOTE:
1. This parameter is measured at characterization but not tested.

PIN DESCRIPTION

Pin Names	Description
Dx	D flip-flop data inputs
CP	Clock Pulse for the register. Enters data on LOW-to-HIGH transition.
Ox	3-State Outputs (TRUE)
$\overline{O}$x	3-State Outputs (INVERTED)
$\overline{OE}$	Active LOW 3-State Output Enable Input

FUNCTION TABLE(1)

	Inputs			Outputs	Internal
Function	$\overline{OE}$	CP	Dx	Qx	$\overline{Q}$x
High-Z	H	L	X	Z	NC
	H	H	X	Z	NC
Load Register	L	↑	L	L	H
	L	↑	H	H	L
	H	↑	L	Z	H
	H	↑	H	Z	L

NOTE:
1. H = HIGH Voltage Level
   X = Don't Care
   L = LOW Voltage Level
   Z = High Impedance
   NC = No Change
   ↑ = LOW-to-HIGH transition

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified: V_{LC} = 0.2V; V_{HC} = V_{CC} - 0.2V
Commercial: T_A = 0°C to +70°C, V_{CC} = 5.0V ±5%, Military: T_A = -55°C to +125°C, V_{CC} = 5.0V ±10%

Symbol	Parameter	Test Conditions[1]		Min.	Typ.[2]	Max.	Unit
V_{IH}	Input HIGH Level	Guaranteed Logic HIGH Level		2	—	—	V
V_{IL}	Input LOW Level	Guaranteed Logic LOW Level		—	—	0.8	V
I_{IH}	Input HIGH Current	V_{CC} = Max.	V_I = V_{CC}	—	—	5	µA
			V_I = 2.7V	—	—	5[4]	
I_{IL}	Input LOW Current		V_I = 0.5V	—	—	–5[4]	
			V_I = GND	—	—	–5	
I_{OZH}	Off State (High Impedance) Output Current	V_{CC} = Max.	V_O = V_{CC}	—	—	10	µA
			V_O = 2.7V	—	—	10[4]	
I_{OZL}			V_O = 0.5V	—	—	–10[4]	
			V_O = GND	—	—	–10	
V_{IK}	Clamp Diode Voltage	V_{CC} = Min., I_{IN} = –18mA		—	–0.7	–1.2	V
I_{OS}	Short Circuit Current	V_{CC} = Max., V_O = GND[3]		–60	–120	—	mA
V_{OH}	Output HIGH Voltage	V_{CC} = 3V, V_{IN} = V_{LC} or V_{HC}, I_{OH} = –32µA		V_{HC}	V_{CC}	—	V
		V_{CC} = Min, V_{IN} = V_{IH} or V_{IL}	I_{OH} = –300µA	V_{HC}	V_{CC}	—	
			I_{OH} = –12mA MIL	2.4	4.3	—	
			I_{OH} = –15mA COM'L	2.4	4.3	—	
V_{OL}	Output LOW Voltage	V_{CC} = 3V, V_{IN} = V_{LC} or V_{HC}, I_{OL} = 300µA		—	GND	V_{LC}	V
		V_{CC} = Min, V_{IN} = V_{IH} or V_{IL}	I_{OL} = 300µA	—	GND	V_{LC}[4]	
			I_{OL} = 32mA MIL	—	0.3	0.5	
			I_{OL} = 48mA COM'L	—	0.3	0.5	

NOTES:
1. For conditions shown as Min. or Max., use appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical values are at V_{CC} = 5.0V, +25°C ambient and maximum loading.
3. Not more than one output should be tested at one time. Duration of the test should not exceed one second.
4. This parameter is guaranteed but not ttested.

POWER SUPPLY CHARACTERISTICS

V_{LC} = 0.2V; V_{HC} = V_{CC} - 0.2V

Symbol	Parameter	Test Conditions[1]		Min.	Typ.[2]	Max.	Unit
I_{CC}	Quiescent Power Supply Current	V_{CC} = Max. $V_{IN} \geq V_{HC}$; $V_{IN} \leq V_{LC}$		—	0.2	1.5	mA
ΔI_{CC}	Quiescent Power Supply Current TTL Inputs HIGH	V_{CC} = Max. V_{IN} = 3.4V[3]		—	0.5	2	mA
I_{CCD}	Dynamic Power Supply Current[4]	V_{CC} = Max. Outputs Open $\overline{OE}$ = GND One Input Toggling 50% Duty Cycle	$V_{IN} \geq V_{HC}$ $V_{IN} \leq V_{LC}$	—	0.15	0.25	mA/ MHz
I_C	Total Power Supply Current[6]	V_{CC} = Max. Outputs Open f_{CP} = 10MHz 50% Duty Cycle $\overline{OE}$ = GND fi = 5MHz One Bit Toggling	$V_{IN} \geq V_{HC}$ $V_{IN} \leq V_{LC}$ (FCT)	—	1.7	4	mA
			V_{IN} = 3.4V V_{IN} = GND	—	2.2	6	
		V_{CC} = Max. Outputs Open f_{CP} = 10MHz 50% Duty Cycle $\overline{OE}$ = GND fi = 2.5MHz Eight Bits Toggling	$V_{IN} \geq V_{HC}$ $V_{IN} \leq V_{LC}$ (FCT)	—	4	7.8[5]	
			V_{IN} = 3.4V V_{IN} = GND	—	6.2	16.8[5]	

NOTES:

1. For conditions shown as Min. or Max., use appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical values are at V_{CC} = 5.0V, +25°C ambient.
3. Per TTL driven input (V_{IN} = 3.4V). All other inputs at V_{CC} or GND.
4. This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
5. Values for these conditions are examples of ΔI_{CC} formula. These limits are guaranteed but not tested.
6. $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$
   $I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD} (f_{CP}/2 + fiNi)$
   I_{CC} = Quiescent Current
   ΔI_{CC} = Power Supply Current for a TTL High Input (V_{IN} = 3.4V)
   D_H = Duty Cycle for TTL Inputs High
   N_T = Number of TTL Inputs at D_H
   I_{CCD} = Dynamic Current caused by an Input Transition Pair (HLH or LHL)
   f_{CP} = Clock Frequency for register devices (zero for non-register devices)
   fi = Input Frequency
   Ni = Number of Inputs at fi

All currents are in milliamps and all frequencies are in megahertz.

SWITCHING CHARACTERISTICS OVER OPERATING RANGE - INDUSTRIAL

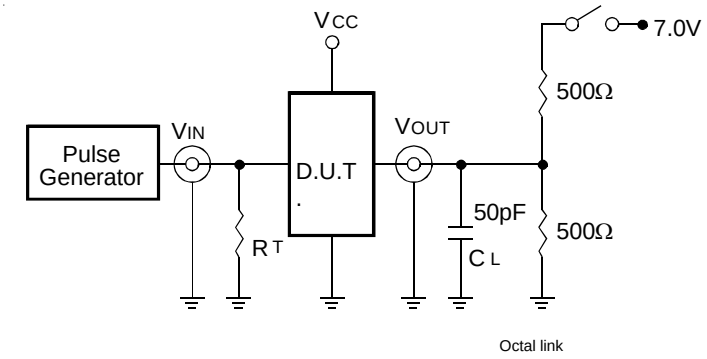
Symbol	Parameter	Condition[1]	74FCT374A		74FCT374C		Unit
			Min.[2]	Max.	Min.[2]	Max.	
t_{PLH} t_{PHL}	Propagation Delay CP to Qx	C_L = 50pF R_L = 500Ω	2	6.5	2	5.2	ns
t_{PZH} t_{PZL}	Output Enable Time		1.5	6.5	1.5	5.5	ns
t_{PHZ} t_{PLZ}	Output Disable Time		1.5	5.5	1.5	5	ns
t_{SU}	Set-up Time HIGH or LOW Dx to CP		2	—	2	—	ns
t_H	Hold Time HIGH or LOW Dx to CP		1.5	—	1.5	—	ns
t_W	CP Pulse Width HIGH or LOW[3]		5	—	5	—	ns

SWITCHING CHARACTERISTICS OVER OPERATING RANGE - MILITARY

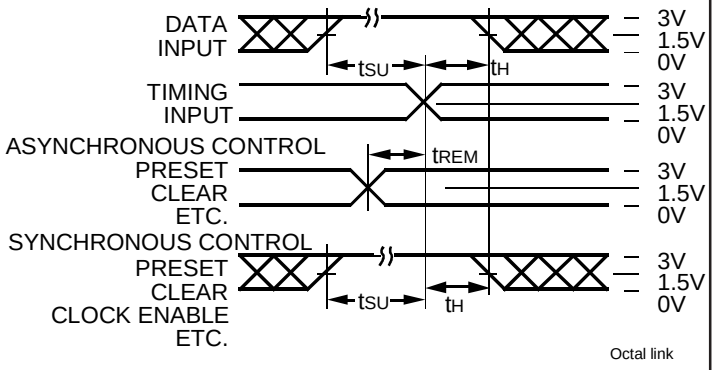
Symbol	Parameter	Condition[1]	54FCT374		54FCT374A		Unit
			Min.[2]	Max.	Min.[2]	Max.	
t_{PLH} t_{PHL}	Propagation Delay CP to Qx	C_L = 50pF R_L = 500Ω	2	11	2	7.2	ns
t_{PZH} t_{PZL}	Output Enable Time		1.5	14	1.5	7.5	ns
t_{PHZ} t_{PLZ}	Output Disable Time		1.5	8	1.5	6.5	ns
t_{SU}	Set-up Time HIGH or LOW Dx to CP		2	—	2	—	ns
t_H	Hold Time HIGH or LOW Dx to CP		1.5	—	1.5	—	ns
t_W	CP Pulse Width HIGH or LOW[3]		7	—	6	—	ns

NOTES:
1. See test circuit and waveforms.
2. Minimum limits are guaranteed but not tested on Propagation Delays.
3. This parameter is guaranteed but not tested.

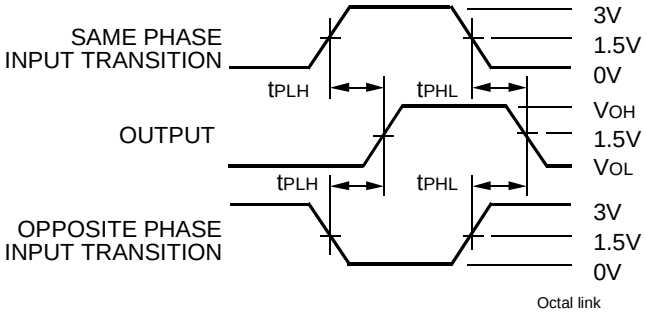
TEST CIRCUITS AND WAVEFORMS



Test Circuits for All Outputs



Set-Up, Hold, and Release Times



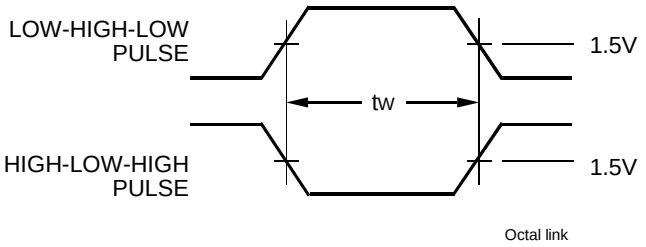
Propagation Delay

SWITCH POSITION

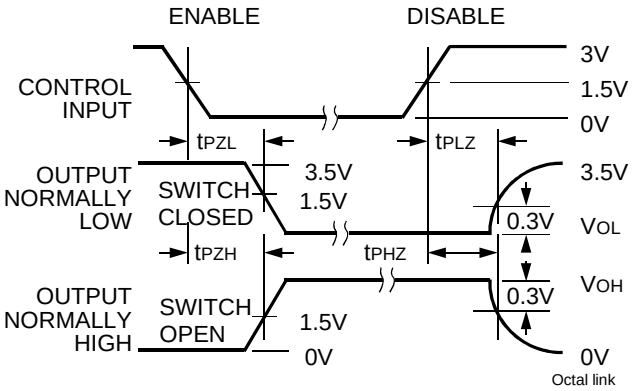
Test	Switch
Open Drain Disable Low Enable Low	Closed
All Other Tests	Open

DEFINITIONS:

C_L = Load capacitance: includes jig and probe capacitance.
R_T = Termination resistance: should be equal to Z_{OUT} of the Pulse Generator.



Pulse Width

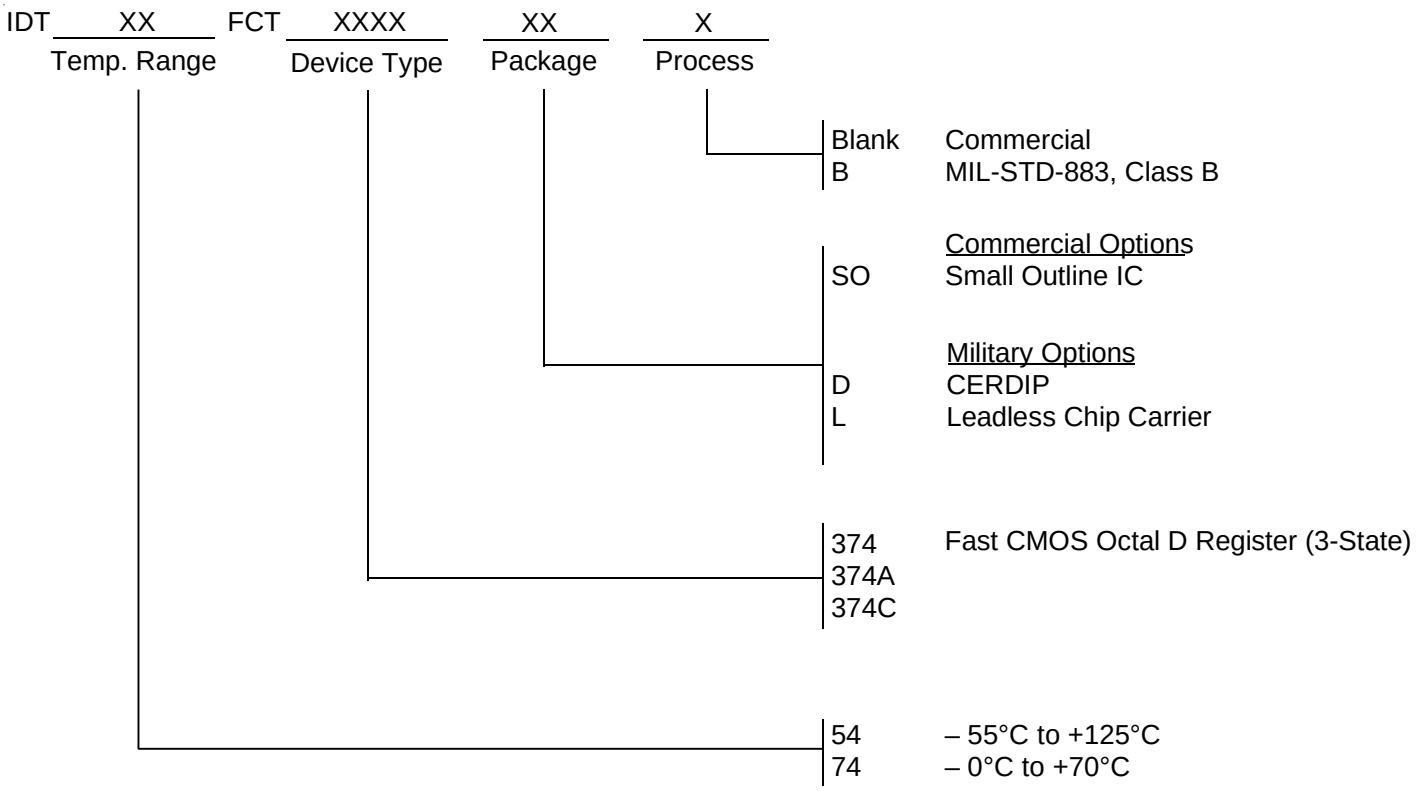


Enable and Disable Times

NOTES:

1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.
2. Pulse Generator for All Pulses: Rate ≤ 1.0MHz; Z_O ≤ 50Ω; t_F ≤ 2.5ns; t_R ≤ 2.5ns.

ORDERING INFORMATION



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